

Substitute for Form 1449 A & B/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

1

of

1

Complete if Known

Application Number	09/824,751
Confirmation Number	9722
Filing Date	April 04, 2001
First Named Inventor	Hiroki KOIKE
Art Unit	2818
Examiner Name	Esaw T. Abraham
Attorney Docket Number	Q63945

OCT. 29 2004

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
EA		Byung-Gil Jeon et al., "A novel cell charge evaluation scheme and rest method for 4 Mb nonvolatile ferroelectric RAM" ICVC '99. 6th INTERNATIONAL CONFERENCE ON VLSI AND CAD (CAT. NO. 99EX361), ICVC '99 6TH INTERNATIONAL CONFERENCE IN VLSI AND CAD, SEOUL, SOUTH KOREA, 26-27 OCT. 1999, pages 281-284, XP002271012 1999, Piscataway, NJ, USA IEEE, USA ASBN: 0-7803-5727-2.	
EA		Byung-Gil Jeon et al.: "A 0.4 μ m, 3.3 V 1T1C 4 Mb nonvolatile ferroelectric RAM with fixed bit-line reference voltage scheme and data protection circuit", 2000 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE. DIGEST OF TECHNICAL PAPERS (CAT. NO. 00CH37056), 2000 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE. DIGEST OF TECHNICAL PAPERS, SAN FRANCISCO, CA, USA, IEEE, USA ISBN: 0-7803-5853-8	

Examiner Signature

Esaw Abraham

Date Considered

03/03/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.